



# CERTIFICATE OF MAILING 37 C.F.R. § 1.8

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the date below:

March 2, 2005

Date

**PATENT** 

#### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

ELFIDO COSS, JR. PATRICK M. COWAN RICHARD J. MARKLE TOM TSE

Serial No.: 10/700,175

Filed: November 3, 2003

For: FAULT DETECTION AND CONTROL

METHODOLOGIES FOR ION

IMPLANTATION PROCESSES, AND SYSTEM FOR PERFORMING SAME

Group Art Unit: 2812

Examiner: Unknown

Atty. Dkt. No.: 2000.088500/TT4616

Customer No.: 23720

#### SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56, it is respectfully requested that this Supplemental Information Disclosure Statement be entered and the documents listed on attached Form PTO-1449 be considered by the Examiner and made of record. Copies of the listed documents required by 37 C.F.R. § 1.98(a)(2) are enclosed for the convenience of the Examiner.

In accordance with 37 C.F.R §§ 1.97(g),(h), this Supplemental Information Disclosure

Statement is not to be construed as a representation that a search has been made, and is not to be

construed to be an admission that the information cited is, or is considered to be, material to

patentability as defined in 37 C.F.R. § 1.56(b).

In accordance with 37 C.F.R § 1.97(e)(1), Applicants hereby certify that each item of

information contained in this Supplemental Information Disclosure Statement was cited in a

communication from a foreign patent office in a counterpart foreign application not more than

three months prior to the filing of the present statement, as evidenced by the date of the enclosed

PCT Search Report.

Applicants respectfully request that the listed documents be made of record in the present

case.

Respectfully submitted,

WILLIAMS, MORGAN & AMERSON

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| A CONTRACTOR OF THE PARTY OF TH | Atty. Docket No.<br>2000.088500/TT4616                                      | Serial No.<br>10/700,175   |  |
| Applicant's  | Applicant Elfido Coss, Jr., Patrick M. Cowan, Richard J. Markle and Tom Tse |  |  |
| Information Disclosure Statement   |   |  |  |
| ry)  | Filing Date:<br>November 3, 2003  | Group:<br>2812   |  |
| Foreign Patent Documents   |   | Other Art  |  |
| See Page 1   |   | See Page 1   |  |
|  | TATEMENT  ry)  Foreign I  | Applicant's Applicant Elfido Coss, Jr., Patrick and Tom Tse  Filing Date: November 3, 2003  Foreign Patent Documents |  |

### **U.S. Patent Documents**

| Exam.<br>Init. | Ref.<br>Des. | Document<br>Number | Date    | Name            | Class | Sub<br>Class | Filing Date of App. |
|----------------|--------------|--------------------|---------|-----------------|-------|--------------|---------------------|
|                | A2           | 6,055,460          | 4/25/00 | Shopbell        | 700   | 121          |                     |
|                | A3           | 2002/0055801 A1    | 5/09/02 | Reiss et al.    | 700   | 111          |                     |
| -              | A4           | 2003/0042427 A1    | 3/06/03 | Sullivan et al. | 250   | 397          |                     |
|                | A5           |                    |         |                 |       |              |                     |
|                | A6           |                    |         |                 |       |              |                     |

## **Foreign Patent Documents**

| Exam.<br>Init. | Ref.<br>Des. | Document<br>Number | Date | Country | Class | Sub<br>Class | Translation<br>Yes/No |
|----------------|--------------|--------------------|------|---------|-------|--------------|-----------------------|
|                | B1           |                    |      |         |       |              |                       |
|                | B2           |                    |      |         |       |              |                       |
|                | В3           |                    |      |         |       |              |                       |

# Other Art (Including Author, Title, Date Pertinent Pages, Etc.)

| Exam.<br>Init. | Ref.<br>Des. | Citation  |  |  |  |
|----------------|--------------|---|--|--|--|
|                | C1           | PCT Search Report from PCT/US2004/017617, dated 12/02/04  |  |  |  |
|                | C2           | Rendon et al., "Ion Implant Data Log Analysis for Process Control and Fault Detection," IEEE, pp. 331-334, 2002 |  |  |  |
|                | C3           |   |  |  |  |

| Examiner: | DATE CONSIDERED: |
|-----------|------------------|

EXAMINER: INITIAL IF REFERENCE CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.